

Notice of References Cited	Application/Control No. 10/620,675		Applicant(s)/Patent Under R examination PUNSALAN ET AL.	
	Examiner Dah-Wei D. Yuan		Art Unit 1745	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2001/0014420	08-2001	TAKEUCHI et al.	429/209
*	B	US-2002/0172871	11-2002	Schucker, Robert C.	429/304
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NON-PATENT DOCUMENTS

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